


<b>Search Notes</b>  	<b>Application/Control No.</b>  10572752	<b>Applicant(s)/Patent Under Reexamination</b>  NAKAMURA ET AL.
	<b>Examiner</b>  Jennifer F Chang	<b>Art Unit</b>  4158

SEARCHED			
Class	Subclass	Date	Examiner
343	788	11/13/2007	Jennifer F. Chang
343	787	11/19/2008	Jennifer F. Chang

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search History	11/13/2007	Jennifer F. Chang
Inventor Search in eDAN	11/13/2007	Jennifer F. Chang
EAST Search History	6/5/2008	Jennifer F. Chang

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/JENNIFER F CHANG/ Examiner.Art Unit 2821	
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